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CONTENTS OF VOLUME 30 NUMBERS 117–120

Articles 1, 137, 247, 365
Book Reviews..... 113, 229, 347, 000
Letters to the Editor 135
Corrections 469
Editorial Collaborators..... 471

Index to Volume 30
Articles, by Author 473
Books Reviewed, by Author 474
Reviewers 476

INDEX TO VOLUME 30 (1988)

ARTICLES, BY AUTHOR

Allen, O. B. (*see* Newcombe, P. A.)
Amin, Raid W. (*see* Reynolds, Marion R., Jr.)
Arnold, Jesse C. (*see* Reynolds, Marion R., Jr.)
Atkinson, A. C., "Transformations Unmasked," 311 (*also see* Donev, A. N.)
Bain, Lee J. (*see* Shiue, Wei-Kei)
Banerjee, P. K., and Rahim, M. A., "Economic Design of $\bar{x}$-Control Charts Under Weibull Shock Models," 407
Beal, S. L., and Sheiner, L. B., "Heteroscedastic Nonlinear Regression," 327
Beckman, Richard J. (*see* Moore, Leslie M.)
Beneke, Margarita, Leemis, Lawrence M., Schlegel, Robert E., and Foote, Bobbie L., "Spectral Analysis in Quality Control: A Control Chart Based on the Periodogram," 63
Bhattacharyya, G. K. (*see* Guttman, I.)
Birch, Jeffrey B. (*see* Walker, Esteban)
Box, George, "Signal-to-Noise Ratios, Performance Criteria, and Transformations," 1; Response, 38
Carroll, R. J., Sacks, J., and Spiegelman, C. H., "A Quick and Easy Multiple-Use Calibration-Curve Procedure," 137
Carroll, Raymond J., and Ruppert, David, Discussion of Box, George, 30
Chang, Ih, Tiao, George C., and Chen, Chung, "Estimation of Time Series Parameters in the Presence of Outliers," 193
Chen, Chung (*see* Chang, Ih)
Cheng, R. C. H., and Iles, T. C., "One-Sided Confidence Bands for Cumulative Distribution Functions," 155
Crosier, Ronald B., "Multivariate Generalizations of Cumulative Sum Quality-Control Schemes," 291
Davis, Charles B., and McNichols, Roger J., Correction, 469
D'Errico, John R., and Zaino, Nicholas A., Jr., "Statistical Tolerancing Using a Modification of Taguchi's Method," 397
Donev, A. N., and Atkinson, A. C., "An Adjustment Algorithm for the Construction of Exact *D*-Optimum Experimental Designs," 429
Draper, Norman R., and Guttman, Irwin, "An Index of Rotatability," 105
Draper, Norman R., and John, J. A., "Response-Surface Designs for Quantitative and Qualitative Variables," 423
Draper, Norman R., and Sanders, Elizabeth R., "Designs for Minimum Bias Estimation," 319
Engelhardt, Max (*see* Shiue, Wei-Kei)
Fairbanks, Kenneth, "A Two-Stage Life Test for the Exponential Parameter," 175
Fickas, E. T. (*see* Martz, H. F.)
Follmann, Dean A., and Goldberg, Matthew S., "Distinguishing Heterogeneity From Decreasing Hazard Rates," 389
Foote, Bobbie L. (*see* Beneke, Margarita)
Galbraith, R. F., "Graphical Display of Estimates Having Differing Standard Errors," 271
Goldberg, Matthew S. (*see* Follmann, Dean A.)
Gunter, Berton, Discussion of Box, George, 32
Guttman, I., Johnson, R. A., Bhattacharyya, G. K., and Reiser, B., "Confidence Limits for Stress-Strength Models With Explanatory Variables," 161
Guttman, Irwin (*see* Draper, Norman R.)
Hahn, G. J., and Raghunathan, T. E., "Combining Information From Various Sources: A Prediction Problem and Other Industrial Applications," 41
Hinkley, D. V., and Wang, S., "More About Transformations and Influential Cases in Regression," 435
Iles, T. C. (*see* Cheng, R. C. H.)
John, J. A. (*see* Draper, Norman R.)
Johnson, R. A. (*see* Guttman, I.)
Kalbfleisch, J. D., and Lawless, J. F., "Estimation of Reliability in Field-Performance Studies," 365; Response, 387
Kao, Edward P. C., "Computing the Phase-Type Renewal and Related Functions," 87
Khuri, A. I., "A Measure of Rotatability for Response-Surface Designs," 95
Lawless, J. F. (*see* Kalbfleisch, J. D.)
Leemis, Lawrence M. (*see* Beneke, Margarita)

León, Ramon V. (*see* Shoemaker, Anne C.)
Lombard, F., "Detecting Change Points by Fourier Analysis," 305
Martz, H. F., Waller, R. A., and Fickas, E. T., "Bayesian Reliability Analysis of Series Systems of Binomial Subsystems and Components," 143
McNichols, Roger J. (*see* Davis, Charles B.)
Moore, Leslie M., and Beckman, Richard J., "Approximate One-Sided Tolerance Bounds on the Number of Failures Using Poisson Regression," 283
Nachlas, Joel A. (*see* Reynolds, Marion R., Jr.)
Nair, Vijayan N., Discussion of Kalbfleisch, J. D., and Lawless, J. F., 379
Nair, Vijayan N., and Pregibon, Daryl, "Analyzing Dispersion Effects From Replicated Factorial Experiments," 247; Discussion of Box, George, 24
Nelson, Peter R., "Testing for Interactions Using the Analysis of Means," 53
Newcombe, P. A., and Allen, O. B., "A Three-Class Procedure for Acceptance Sampling by Variables," 415
O'Reilly, F. J., and Stephens, M. A., "Transforming Censored Samples for Testing Fit," 79
Panjabi, M. M. (*see* Walter, S. D.)
Parker, I., "Transformations and Influential Observations in Minimum Sum of Absolute Errors Regression," 215
Parr, William C., Discussion of Box, George, 22
Piepel, Gregory F., "A Note on Models for Mixture-Amount Experiments When the Total Amount Takes a Zero Value," 449
Pregibon, Daryl (*see* Nair, Vijayan N.)
Raghunathan, T. E. (*see* Hahn, G. J.)
Rahim, M. A. (*see* Banerjee, P. K.)
Reiser, B. (*see* Guttman, I.)
Reynolds, Marion R., Jr., Amin, Raid W., Arnold, Jesse C., and Nachlas, Joel A., "$\bar{X}$ Charts With Variable Sampling Intervals," 181
Robinson, Jeffrey A., Discussion of Kalbfleisch, J. D., and Lawless, J. F., 384
Ruppert, David (*see* Carroll, Raymond J.)
Sacks, J. (*see* Carroll, R. J.)
Sanders, Elizabeth R. (*see* Draper, Norman R.)
Schlegel, Robert E. (*see* Beneke, Margarita)
Sheiner, L. B. (*see* Beal, S. L.)
Shiue, Wei-Kei, Bain, Lee J., and Engelhardt, Max, "Test of Equal Gamma-Distribution Means With Unknown and Unequal Shape Parameters," 169
Shoemaker, Anne C., Tsui, Kwok-Leung, and León, Ramon V., Discussion of Box, George, 19
Simonoff, Jeffrey S., "Detecting Outlying Cells in Two-Way Contingency Tables Via Backwards-Stepping," 339; "Regression Diagnostics to Detect Nonrandom Missingness in Linear Regression," 205
Spiegelman, C. H. (*see* Carroll, R. J.)
Steinberg, David M., "Factorial Experiments With Time Trends," 259
Stephens, M. A. (*see* O'Reilly, F. J.)
Tiao, George C. (*see* Chang, Ih)
Tsai, Chih-Ling, "Power Transformations and Reparameterizations in Nonlinear Regression Models," 441
Tsui, Kwok-Leung (*see* Shoemaker, Anne C.)
Ullman, Neil R., Discussion of Box, George, 36
Walker, Esteban, and Birch, Jeffrey B., "Influence Measures in Ridge Regression," 221; Correction, 470
Waller, R. A. (*see* Martz, H. F.)
Walter, S. D., and Panjabi, M. M., "Experimental Errors in the Observation of Body Joint Kinematics," 71
Wang, S. (*see* Hinkley, D. V.)
Zaino, Nicholas A., Jr. (*see* D'Errico, John R.)

BOOKS REVIEWED, BY AUTHOR

Aitchison, J., *The Statistical Analysis of Compositional Data*, Gregory F. Piepel, 120
Anderson, David R., Sweeney, Dennis J., and Williams, Thomas A., *Statistics: Concepts and Applications*, Annabeth Propst, 461
Anderson, T. W., and Eynon, B. P., *MINITAB Guide to the Statistical Analysis of Data*, Allen H. Reed, 236
Anderson, T. W., and Sclove, S. L., *The Statistical Analysis of Data*, Allen H. Reed, 236
Bain, Lee J., and Engelhardt, Max, *Introduction to Probability and Mathematical Statistics*, Eric R. Ziegel, 353
Basu, Asit (ed.), *Reliability and Quality Control*, Eric Ziegel, 455
Bayne, C. K., and Rubin, I. B., *Practical Experimental Designs and Optimization Methods for Chemists*, Eric Ziegel, 119
Blinchikoff, H., and Zverev, A., *Filtering in the Time and Frequency Domains*, Eric R. Ziegel, 245
Bocklebank, John C., and Dickey, David A., *SAS System for Forecasting Time Series*, Darryl J. Downing, 118
Bos, T. (*see* Newbold, P.)
Box, G. E. P., and Draper, N. R., *Empirical Model Building and Response Surfaces*, Anne Freeny, 229
Bunke, H., and Bunke, O. (eds.), *Statistical Inference in Linear Models*, Eric Ziegel, 463
Bunke, O. (*see* Bunke, H.)
Bury, Karl, *Statistical Models in Applied Science*, Steven E. Rigdon, 129
Casella, G. (*see* McCulloch, C.)
Caulcott, Roland, *Statistics in Research and Development*, Eric Ziegel, 122
Chalmer, Bruce J., *Understanding Statistics*, Joseph G. Pigeon, 121
Cheremisinoff, N. P., *Practical Statistics for Engineers and Scientists*, David Crosby, 234
Cho, Chin-Kuei, *Quality Programming: Developing and Testing Software With Statistical Quality Control*, Michael J. Mazu, 467
Clark, V. A. (*see* Dunn, O. J.)
Cooley, W., and Lohnes, P., *Multivariate Data Analysis*, Eric Ziegel, 130
Cox, C. Philip, *A Handbook of Introductory Statistical Methods*, Nancy C. Hassett, 233
Cox, Neil D., *How to Perform Statistical Tolerance Analysis*, David Coleman, 114

Daniel, Wayne, *Biostatistics: A Foundation for Analysis in the Health Sciences*, Eric R. Ziegel, 243
Das, M. N., and Giri, N. C., *Design and Analysis of Experiments*, R. Daniel Meyer, 241
DeAntoni, F., Lauro, N., and Rezzi, A., *COMPSTAT: Proceedings in Computational Statistics*, Eric R. Ziegel, 245
DePriest, Douglas J. (*see* Wegman, Edward J.)
Devore, Jay, and Peck, Roxy, *Statistics: The Exploration and Analysis of Data*, Kenneth D. Kotnour, 460
Devore, Jay L., *Probability and Statistics for Engineering and the Sciences*, A. Goldman, 235
Dickey, David A. (*see* Bocklebank, John C.)
Dietrich, Frank, II, and Kearns, Thomas J., *Basic Statistics: An Inferential Approach*, Marvin H. J. Gruber, 124
Dietrich, Frank H., II (*see* McClave, James T.)
Draper, N. R. (*see* Box, G. E. P.)
Duncan, A. J., *Quality Control and Industrial Statistics*, Eric R. Ziegel, 357
Dunn, O. J., and Clark, V. A., *Applied Statistics: Analysis of Variance and Regression*, Eric Ziegel, 462
Edosomwan, J. A., *Integrating Productivity and Quality Management*, Eric R. Ziegel, 358
Engelhardt, Max (*see* Bain, Lee J.)
Fowlkes, Edward B., *A Folio of Distributions*, Eric Ziegel, 462
Freeman, Daniel H., Jr., *Applied Categorical Data Analysis*, Alan Agresti, 456
Freund, R., Littell, R., and Spector, P., *SAS System for Linear Models*, Mervyn G. Marasinghe, 116
Freund, R. J., and Littell, R. C., *SAS System for Regression*, Robert L. Mason, 117
Gallant, A. Ronald, *Nonlinear Statistical Models*, Douglas Bates, 453
Gelsema, Edzard S., and Kanal, Laveen N. (eds.), *Pattern Recognition in Practice II*, Daniel Q. Naiman, 128
Gibbons, Jean, *Nonparametric Statistical Inference*, Eric Ziegel, 457
Gilbert, Richard O., *Statistical Methods for Environmental Pollution Monitoring*, John Warren, 348
Giri, N. C. (*see* Das, M. N.)
Goldberg, J. (*see* Potter, M.)
Griffith, Gary, *Quality Technician's Handbook*, Gene Placzkowski, 132
Hamburg, Morris, *Statistical Analysis for Decision Making*, Thomas W. Calvin, 235
Harrington, H. James, *Poor-Quality Cost*, Marie Gaudard, 358
Hassett, Matthew (*see* Weiss, Neil)
Hogg, R. V., and Ledolter, J., *Engineering Statistics*, J. L. Hansen, 347
Horton, Raymond, *The General Linear Model*, Mani Y. Lakshminarayanan, 130
Jaffe, A. J., and Spirer, Herbert F., *Misused Statistics: Straight Talk for Twisted Numbers*, Boris Iglewicz, 121
John, J. A., *Cyclic Designs*, Max D. Morris, 455
Johnson, Mark E., *Multivariate Statistical Simulation*, Ian Jolliffe, 232
Jolliffe, I. T., *Principal Component Analysis*, Colin Goodall, 351
Jones, L. (*see* Kern, J.)
Jones, Lyle (ed.), *The Collected Works of John W. Tukey* (Vols. 3 and 4), Eric R. Ziegel, 363
Kachigan, Sam, *Statistical Analysis*, Mark Marcucci, 235
Kanal, Laveen N. (*see* Gelsema, Edzard S.)
Kearns, Thomas J. (*see* Dietrich, Frank, II)
Kern, J., Riley, J., and Jones, L. (eds.), *Human Resources Management*, Eric R. Ziegel, 359
Kimber, Raymond J. (*see* Walsh, Loren)
Kinnison, Robert R., *Applied Extreme Value Statistics*, Steven W. Rust, 126
Klagge, J. (*see* O'Keeffe, Linda)
Kleijnen, Jack P. C., *Statistical Tools for Simulation Practitioners*, Henry C. Thode, Jr., 464
Klugh, Henry, *Statistics: The Essentials for Research*, Patricia Langenberg, 459
Koopmans, Lambert, *Introduction to Contemporary Statistical Methods*, Robert Schaefer, 353
Lauro, N. (*see* DeAntoni, F.)
Ledolter, J. (*see* Hogg, R. V.)
Leskiw, Donald M. (*see* Miller, Kenneth S.)
Lewis, Frank L., *Optimal Estimation With an Introduction to Stochastic Control*, Richard M. Stanley, 359
Linhart, H., and Zucchini, W., *Model Selection*, Ramon C. Littell, 115
Littell, R. (*see* Freund, R.)
Little, R., and Rubin, D., *Statistical Analysis With Missing Data*, Subir Ghosh, 455
Lohnes, P. (*see* Cooley, W.)
Mathews, John H., *Numerical Methods for Computer Science, Engineering, and Mathematics*, Eric R. Ziegel, 245
McClave, James T., and Dietrich, Frank H., II, *A First Course in Statistics*, David L. Farnsworth, 124; *Statistics*, Gregory C. McLaughlin, 125
McCulloch, C., Schwager, S., Casella, G., and Searle, S. (eds.), *Statistical Design: Theory and Practice*, Eric R. Ziegel, 242
Mendel, Jerry M., *Lessons in Digital Estimation Theory*, Douglas J. DePriest, 128
Mendenhall, William, *Introduction to Probability and Statistics*, David Sylwester, 356
Merks, J. W., *Sampling and Weighing of Bulk Solids*, R. A. Bilonick, 132
Miller, Kenneth S., and Leskiw, Donald M., *An Introduction to Kalman Filtering With Applications*, Alan Julian Izenman, 243
Montgomery, Douglas C., *Introduction to Statistical Quality Control*, Charles Quesenberry, 356
Moses, Lincoln E., *Think and Explain With Statistics*, Annabeth L. Propst, 233
Neelamkavil, Francis, *Computer Simulation and Modelling*, Douglas J. DePriest, 463
Newbold, P., and Bos, T., *Stochastic Parameter Regression Models*, Eric R. Ziegel, 361
Norusis, Marija J., *The SPSS Guide to Data Analysis*, Anita Parunak, 237; *SPSS-X Advanced Statistics Guide*, Mark Von Tress, 239; *SPSS-X Introductory Statistics Guide*, Martin G. Gibson, 237
Oakland, John S., *Statistical Process Control*, Robert L. Perry, 454
O'Keeffe, Linda, and Klagge, J., *Statistical Packages for the IBM PC Family*, Eric Ziegel, 468
Peck, Roxy (*see* Devore, Jay)
Peters, William S., *Counting for Something: Statistical*

Principles and Personalities, R. W. Farebrother, 362
Pike, Ralph W., *Optimization for Engineering Systems*, George Derringer, 131
Potter, M., and Goldberg, J., *Mathematical Methods*, Eric R. Ziegel, 245
Puri, M., Vilaplana, J., and Wertz, W. (eds.), *New Perspectives in Theoretical and Applied Statistics*, Eric R. Ziegel, 356
Rezzi, A. (*see* DeAntoni, F.)
Riley, J. (*see* Kern, J.)
Ripley, Brian D., *Stochastic Simulation*, Jane M. Booker, 231
Rizvi, M. Haseeb (ed.), *Modern Statistical Selection, Part I*, Willis L. Owen, 127
Romano, J., and Siegel, A., *Counterexamples in Probability and Statistics*, Eric R. Ziegel, 240
Ross, Sheldon M., *Introduction to Probability and Statistics for Engineers and Scientists*, Marion J. Reynolds, Jr., 457
Rubin, D. (*see* Little, R.)
Rubin, I. B. (*see* Bayne, C. K.)
Rubinstein, Reuven Y., *Monte Carlo Optimization, Simulation and Sensitivity of Queueing Networks*, John E. Angus, 465
Sachs, Lothar, *A Guide to Statistical Methods and to the Pertinent Literature*, Eric R. Ziegel, 241
Schneider, H., *Truncated and Censored Samples From Normal Populations*, Carolyn Morgan, 118
Schwager, S. (*see* McCulloch, C.)
Sclove, S. L. (*see* Anderson, T. W.)
Searle, S. (*see* McCulloch, C.)
Shapiro, Samuel S., *How to Test Normality and Other Distributional Assumptions*, David Coleman, 114
Shaw, Gareth, and Wheeler, Dennis, *Statistical Techniques in Geographical Analysis*, Daniel A. Griffith, 348
Siegel, A. (*see* Romano, J.)
Sinha, S. K., *Reliability and Life Testing*, Asit Basu, 131
Snell, E. J., *Applied Statistics: A Handbook of BMDP Analyses*, Eric Ziegel, 468
Sommer, Karl, *Sampling of Powders and Bulk Materials*, R. A. Bilonick, 349
Spector, P. (*see* Freund, R.)
Spirer, Herbert F. (*see* Jaffe, A. J.)
Stigler, Stephen, *The History of Statistics*, Eric Ziegel, 462
Sweeney, Dennis J. (*see* Anderson, David R.)
Tietjen, Gary L., *A Topical Dictionary of Statistics*, Marvin Gruber, 240
Tijms, Henk C., *Stochastic Modelling and Analysis*, P. W. Jones, 361
Tobias, P. A., and Trindade, D., *Applied Reliability*, Michele Carey, 231
Trindade, D. (*see* Tobias, P. A.)
Tukey, John W., *The Collected Works of John W. Tukey* (Vols. 3 and 4), Eric R. Ziegel, 363
Vilaplana, J. (*see* Puri, M.)
Walsh, Loren, Wurster, Ralph, and Kimber, Raymond J. (eds.), *Quality Management Handbook*, Gerald Shea, 243
Wegman, Edward J., and DePriest, Douglas J. (eds.), *Statistical Image Processing and Graphics*, Ronald Thisted, 126
Weiss, Neil, and Hassett, Matthew, *Introductory Statistics*, Paul D. Minton, 354
Wertz, W. (*see* Puri, M.)
Wetherill, G. Barrie, *Regression Analysis With Applications*, Richard F. Gunst, 451
Wheeler, Dennis (*see* Shaw, Gareth)
Williams, Richard H. (*see* Zimmerman, Donald W.)
Williams, Thomas A. (*see* Anderson, David R.)
Winston, Wayne, *Operations Research: Applications and Algorithms*, Eric R. Ziegel, 361
Wonnacott, R. J. (*see* Wonnacott, T. H.)
Wonnacott, T. H., and Wonnacott, R. J., *Regression: A Second Course in Statistics*, Eric Ziegel, 130
Wurster, Ralph (*see* Walsh, Loren)
Zimmerman, Donald W., and Williams, Richard H., *Modern Elementary Statistics, With Theoretical Supplement and BASIC Programming*, Paul J. Smith, 123
Zucchini, W. (*see* Linhart, H.)
Zverev, A. (*see* Blinchikoff, H.)

REVIEWERS

Agresti, Alan, 456
Angus, John E., 465
Basu, Asit, 131
Bates, Douglas, 453
Bilonick, R. A., 132, 349
Booker, Jane M., 231
Calvin, Thomas W., 235
Carey, Michele, 231
Coleman, David, 114
Crosby, David, 234
DePriest, Douglas J., 128, 463
Derringer, George, 131
Downing, Darryl J., 118
Farebrother, R. W., 362
Farnsworth, David L., 124
Freeny, Anne, 229
Gaudard, Marie, 358
Ghosh, Subir, 455
Gibson, Martin G., 237
Goldman, A., 235
Goodall, Colin, 351
Griffith, Daniel A., 348
Gruber, Marvin H. J., 124, 240
Gunst, Richard F., 451
Hansen, J. L., 347
Hassett, Nancy C., 233
Iglewicz, Boris, 121
Izenman, Alan Julian, 243
Jolliffe, Ian, 232
Jones, P. W., 361
Kotnour, Kenneth D., 460
Lakshminarayanan, Mani Y., 130
Langenberg, Patricia, 459
Littell, Ramon C., 115
Marasinghe, Mervyn G., 116
Marcucci, Mark, 235
Mason, Robert L., 117
Mazu, Michael J., 467
McLaughlin, Gregory C., 125
Meyer, R. Daniel, 241
Minton, Paul D., 354
Morgan, Carolyn, 118
Morris, Max D., 455
Naiman, Daniel Q., 128
Owen, Willis L., 127
Parunak, Anita, 237
Perry, Robert L., 454
Piepel, Gregory F., 120
Pigeon, Joseph G., 121
Placzkowski, Gene, 132
Propst, Annabeth L., 233, 461
Quesenberry, Charles, 356
Reed, Allen H., 236
Reynolds, Marion J., Jr., 457
Rigdon, Steven E., 129
Rust, Steven W., 126
Schaefer, Robert, 353

Shea, Gerald, 243
Smith, Paul J., 123
Stanley, Richard M., 359
Sylwester, David, 356
Thisted, Ronald, 126
Thode, Henry C., Jr., 464
Von Tress, Mark, 239
Warren, John, 348
Ziegel, Eric R., 119, 122, 130, 240, 241, 242, 243, 245, 353, 356, 357, 358, 359, 361, 363, 455, 457, 462, 463, 464